Thermionic graphene/silicon Schottky infrared photodetectors

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S1. LIST OF SYMBOLS AND ACRONYMS

| $\alpha_{l,\mathrm{SLG}}$ | Graphene lattice constant |
|---------------------------|-------------------------------------------------------------------|
| $c_{e,\mathrm{SLG}}$ | Graphene electronic heat capacity |
| C_j | Graphene/Semiconductor junction capacitance |
| $c_{l,\mathrm{SLG}}$ | Graphene lattice heat capacity |
| $C_{q,\mathrm{SLG}}$ | Graphene quantum capacitance |
| CMOS | Complementary metal-oxide-semiconductor |
| CNP | Charge neutrality point |
| D^* | Specific detectivity |
| $d_{ m Au}$ | Au backmirror thickness |
| $d_{n,\mathrm{Si}}$ | n-doped Si layer thickness |
| $d_{ m Si}$ | Undoped Si layer thickness |
| $d_{{ m SiO}_2}$ | Silicon dioxide layer thickness |
| $D_{\rm SLG}$ | Deformation potential for disorder – assisted supercollisions |
| $d_{\rm SLG}$ | Graphene layer thickness |
| $E_{C,\mathrm{Si}}$ | Silicon conduction band energy level |
| $E_{F,\mathrm{Si}}$ | Silicon Fermi level |
| $E_{F,\mathrm{SLG}}$ | Graphene Fermi level |
| $E'_{F,\mathrm{SLG}}$ | Graphene Fermi level before contact with Silicon |
| $E_{F0,SLG}$ | Graphene Fermi level upon contact with Silicon at zero bias |
| $E_{g,\mathrm{Si}}$ | Silicon bandgap |
| e-h | Electron hole pair |
| EPC | Electron phonon coupling |
| e - ph | Electron phonon |
| $e\phi_{\rm Si}$ | Energy difference between Silicon conduction band and fermi level |
| F | Inverse surface coverage ratio |
| FWHM | Full-width at half-maximum |
| $f_{\rm FD}$ | Fermi - Dirac distribution |
| $f_{ m opt}$ | Optics limited operation frequency |

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| $f_{ m RC}$ | Electronics limited operation frequency |
|----------------------|-------------------------------------------------------------------|
| $f_{ m tr}$ | Carriers' transition limited frequency |
| i_d | Dark current |
| i_j | Johnson (thermal) noise current |
| i_n | Total noise current |
| $I_{ m ph}$ | Photocurrent |
| i_s | Shot noise current |
| IPE | Internal photoemission |
| IR | Infrared |
| J_d | Saturation current density at dark |
| $J_{\rm el}$ | Photocurrent density |
| $J_{e-{\rm ph}}$ | Total electron-to-phonon thermal current density |
| J_{op} | Electron-to-optical phonon thermal current density |
| J_R | Total reverse current density under illumination |
| $J_{ m SC}$ | Electron-to-phonon thermal current density due to supercollisions |
| $J_{ m th}$ | Thermal current density due to thermionic emission of carriers |
| $k_{F,\mathrm{SLG}}$ | Graphene Fermi wavevector |
| L | Optical cavity length |
| LDR | Linear dynamical range |
| l | Mean free path for supercollision scattering |
| MWIR | Mid wave infrared |
| N(x) | Bose – Einstein distribution |
| $n_{\rm SLG}^*$ | Free carrier concentration associated with graphene doping |
| $n_{0,\mathrm{SLG}}$ | Initial (before contact) graphene carrier concentration |
| $n_{ m Au}$ | Au layer refractive index |
| $N_{C,\mathrm{Si}}$ | Effective density of states in the conduction band of silicon |
| $N_{d,\mathrm{Si}}$ | Silicon donor concentration |
| $n_{e,\mathrm{SLG}}$ | Graphene electron concentration |
| $n_{h,\mathrm{SLG}}$ | Graphene hole concentration |

| $n_{\rm min,SLG}$ | Graphene minimum carrier density |
|--------------------------|------------------------------------------------------------|
| $n_{ m Si}$ | Silicon layer refractive index |
| $n_{\rm SiO_2}$ | Silicon dioxide layer refractive index |
| $N_{V,\mathrm{Si}}$ | Effective density of states in the valence band of silicon |
| $N_{\alpha,\mathrm{Si}}$ | Silicon acceptor concentration |
| NEP | Noise equivalent power |
| nSi | n – doped Silicon |
| nSLG | n - doped single layer graphene |
| $P_{\rm in}$ | Input power density |
| pSi | p – doped Silicon |
| pSLG | p – doped single layer graphene |
| PD | Photodetector |
| PTh | Photothermionic |
| PV | Photovoltaic |
| Q | Bragg cavity quality factor |
| R | External responsivity |
| R_C | Contact resistance |
| $R_{\rm CW}$ | Quasi-cw illumination external responsivity |
| R_{el} | Sum of series and contact resistance |
| $R_{\rm eq}$ | Equivalent resistance at reverse bias in dark |
| $R_{ m lin}$ | Linear regime external responsivity |
| $R_{\rm peak}$ | Peak external responsivity |
| R_s | Series total resistance |
| $R_{\rm Si}$ | Silicon layer resistance |
| $R_{\rm SLG}$ | Single layer graphene resistance |
| RT | Room temperature |
| S | Single layer graphene geometrical cross section |
| S_0 | Diffraction limited area |
| $s_{ m SLG}$ | Sound velocity on single layer graphene |

| SBH | Schottky barrier height |
|----------------------------------|--------------------------------------------------------------------|
| SC | Semiconductor |
| SLG | Single layer graphene |
| SNR | Signal to noise ratio |
| $T_{e,\mathrm{Si}}$ | Electronic temperature in Silicon |
| $T_{e,\mathrm{SLG}}$ | Electronic temperature in single layer graphene |
| $T_{l,\mathrm{SLG}}$ | Lattice temperature in single layer graphene |
| V_0 | Built in potential in depletion region |
| $v_{F,\mathrm{SLG}}$ | Graphene Fermi velocity |
| V_R | Reverse bias voltage |
| V_{R}^{\prime} | Reverse bias voltage drop in silicon depletion region |
| V_R^{BD} | Reverse bias breakdown potential |
| $v_{\mathrm{sat},Si}$ | Carrier saturation velocity in silicon |
| $\alpha_{\rm inter,SLG}$ | Single layer graphene interband absorption |
| $\alpha_{\rm SLG}$ | Single layer graphene absorption |
| γ_a | Total absorption rate in Bragg cavity |
| γ_d | Total decay rate in Bragg cavity |
| $\Gamma_{\rm SLG-Si}$ | Cooling rate from single layer graphene to Silicon |
| $\gamma_{ m SC}$ | Prefactor for calculation of supercollision scattering |
| $\delta_{n,\mathrm{SLG}}$ | Graphene non-equilibrium carrier density |
| $\Delta E_{F,\mathrm{SLG}}$ | Induced graphene Fermi level shift due to reverse bias |
| $\Delta Q_{D,\mathrm{Si}}$ | Induced change in depletion region charge due to reverse bias |
| $\Delta Q_{ m SLG}$ | Induced change in single layer graphene charge due to reverse bias |
| $\delta \Phi_B$ | Induced change in Schottky barrier height due to reverse bias |
| $\epsilon_{ m Si}$ | Silicon dielectric permittivity |
| $\epsilon_{ m SLG}$ | Single layer graphene dielectric function |
| $\epsilon_{\infty,\mathrm{SLG}}$ | High frequency limit of the graphene dielectric permittivity |
| $\mu_{c,\mathrm{SLG}}$ | Graphene conduction band non-equilibrium chemical potential |
| $\mu_{e,\mathrm{Si}}$ | Electron mobility in Silicon |

| $\mu_{q,\mathrm{SLG}}$ | Carrier mobility in single layer graphene |
|------------------------------|--------------------------------------------------------------------------------|
| $\mu'_{ m SLG}$ | Graphene chemical potential before contact with silicon |
| $\mu_{ m SLG}$ | Graphene equilibrium chemical potential |
| $\mu_{v,\mathrm{SLG}}$ | Graphene valence band non-equilibrium chemical potential |
| $\mu_{0,\mathrm{SLG}}$ | Graphene chemical potential upon contact with silicon at zero bias |
| $ u(\epsilon)$ | Graphene density of electronic states |
| $ ho_{ m SLG}$ | Graphene mass density |
| $\sigma_{ m DC,SLG}$ | Graphene DC conductivity |
| $\sigma_{ m inter}^{ m opt}$ | Graphene interband optical conductivity |
| $\sigma_{ m intra}^{ m opt}$ | Graphene intraband optical conductivity |
| $\sigma_{ m SLG}^{ m opt}$ | Graphene total optical conductivity |
| τ | Total temporal response limit |
| τ_{e-e} | Time scale for relaxation in a Fermi – Dirac distribution in graphene |
| $\tau_{e-\mathrm{ph}}$ | Time scale for electron – phonon scattering in graphene |
| $	au_{ m inj}$ | Time scale for carrier injection from graphene to semiconductor |
| $	au_{ m opt}$ | Free electron relaxation time related to charge carrier's mobility in graphene |
| $	au_{ m ph}$ | Photon lifetime inside the optical cavity |
| $\tau_{\rm pulse}$ | Pulse duration of illumination source |
| $	au_{ m RC}$ | Charge/discharge RC time constant of the diode/circuit combination |
| $	au_{ m tr}$ | Transit time of charge carriers across the depletion zone |
| Φ_B | Schottky barrier height |
| Φ_{B0} | Schottky barrier height upon contact at zero bias |
| Φ_{B0}^{\min} | Lower limit of Schottky barrier height |
| $\Phi_B^{ m CNP}$ | Schottky barrier height in respect to graphene charge neutrality point |
| $\Phi_{\rm Si}$ | Silicon workfunction |
| $\Phi_{ m SLG}^{\prime}$ | Graphene workfunction before contact with silicon |
| $\Phi_{ m SLG}$ | Graphene workfunction upon contact with silicon |
| χ_d | Depletion region width |
| $\chi_{ m Si}$ | Silicon electron affinity |

| $\chi_{ m SLG}$ | Single layer graphene electron affinity |
|---------------------------|-----------------------------------------|
| $\Omega_{i,\mathrm{SLG}}$ | Graphene optical phonon energy |

TABLE S1: Summary of symbols and acronyms used

throughout this work.